

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240800US-2S DIV		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Norihisa ARAI			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
KR	AV	T. UKEDA, et al., "HIGH RELIABILITY TRENCH ISOLATION TECHNOLOGY WITH ELEVATED FIELD OXIDE STRUCTURE FOR SUB-QUARTER MICRON CMOS DEVICES" Solid State Devices and Materials, Yokohama 1996, pgs. 260 - 262.					
	AW	F. ARAI, et al., "HIGH DENSITY (4.4 F ²) NAND FLASH TECHNOLOGY USING SUPER-SHALLOW CHANNEL PROFILE (SSCP) ENGINEERING", IEEE, 2000, pgs. 775 - 778.					
	AX	Seijiro FURUKAWA, "SEMICONDUCTOR DEVICE", Corona Co., Ltd. Pgs. 57 - 59.					
	AY	S. M Sea, Supervised Translated by: Takeishi, Nishi, Kayama, "ULTRA-LSI TECHNOLOGY", Soken Shuppan, pgs. 230 - 237.					
KR	AZ	An article supervised by Takuo Sugano and edited by Tetsuya Iizuka, "DESIGN OF CMOS ULTRA-LSI", Baifu-kan, pgs. 192 - 193.					
Examiner <i>K. Rose</i>					Date Considered <i>9/24/04</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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U.S. PATENT DOCUMENTS							
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
K2	AO	2000-0035711 w/corresponding Japanese application 2000-243979 and English Abstract	06/26/2000	Korea			X
K2	AP	02-246227 w/English Abstract	10/02/1990	Japan			X
	AQ						
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
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	AY						
	AZ						
Examiner <i>[Signature]</i>				<input type="checkbox"/> Additional References sheet(s) attached			
				Date Considered 9/24/04			
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SHEET 1 OF 1

Form PTO 1449
(Modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.
240800US-2S DIV

SERIAL NO.
NEW APPLICATION

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Norihsa ARAI

FILING DATE
HEREWITH

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
KR	AA	5,670,404	09/23/97	DAI			
	AB	6,005,270	12/21/99	NOGUCHI			
	AC	6,049,113	04/11/00	SHIDA			
	AD	6,281,050	08/28/01	SAKAGAMI			
	AE	6,297,082	10/02/01	LIN ET AL.			
KR	AF	6,300,655	10/09/01	EMA ET AL.			
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
KR	AO	6-268178	09/22/94	JAPAN W/ENGLISH ABSTRACT		XX
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner *K. Rose*

Date Considered *9/24/04*

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